

From Eye to Insight



Imaging Software for Industrial Applications

CONFIDENCE IN YOUR RESULTS

Leica Application Suite X (LAS X)



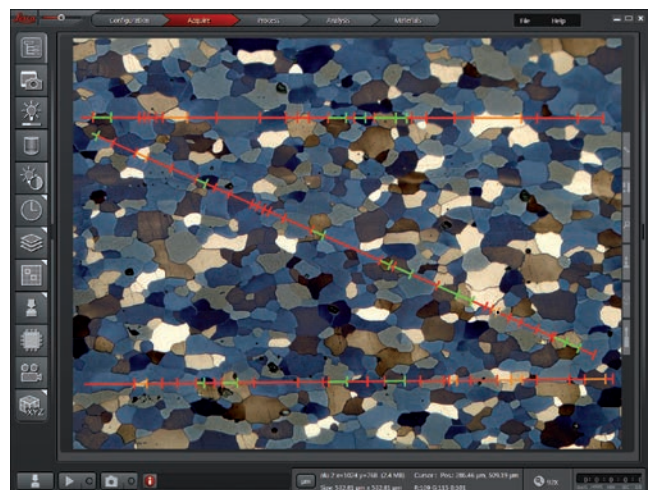
CLEAR COMPREHENSIVE CUSTOMIZABLE

Leica Application Suite (LAS) X helps you to deliver reliable results with confidence. The LAS X software platform is designed to make your daily analysis and documentation tasks faster, easier, and more efficient. You can choose from a range of functions for basic and advanced image analysis.

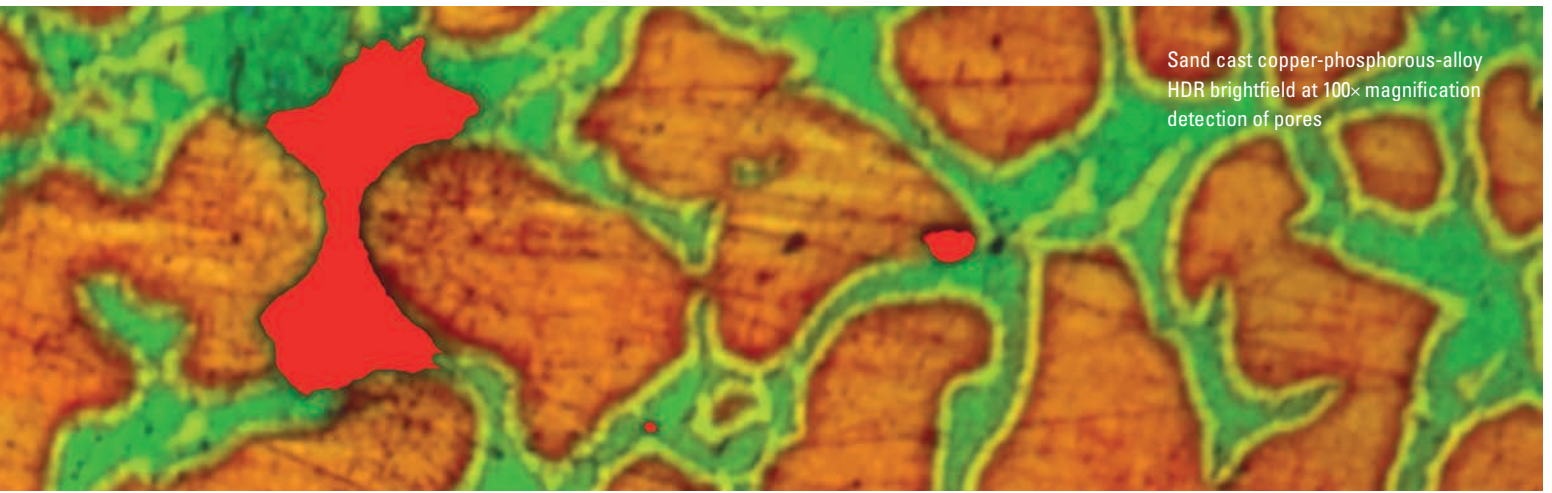
Standard workflow with reporting		Control of Leica microscopes & cameras
	HDR	Acquisition of HDR images
		Advanced image processing
		Basic measurements
		Annotations
		Documentation
Possible add-ons		Digital chart comparison
		Time automated acquisition
		Movie recording

Straight forward single image analysis

- > No matter if you are working with a compound, stereo, or digital microscope, you can control your device in x, y, and z using your mouse.
- > The High Dynamic Range (HDR) and advanced image processing functions provide you with the best image.
- > The simple user interface makes it easy to work with a range of tools for measurements, annotations, and report templates.
- > You can expand your analysis with comparison charts, counting grids with digital reticules, and time-automated acquisition.



Metallography toolbox, grain size



Sand cast copper-phosphorous-alloy
HDR brightfield at 100× magnification
detection of pores



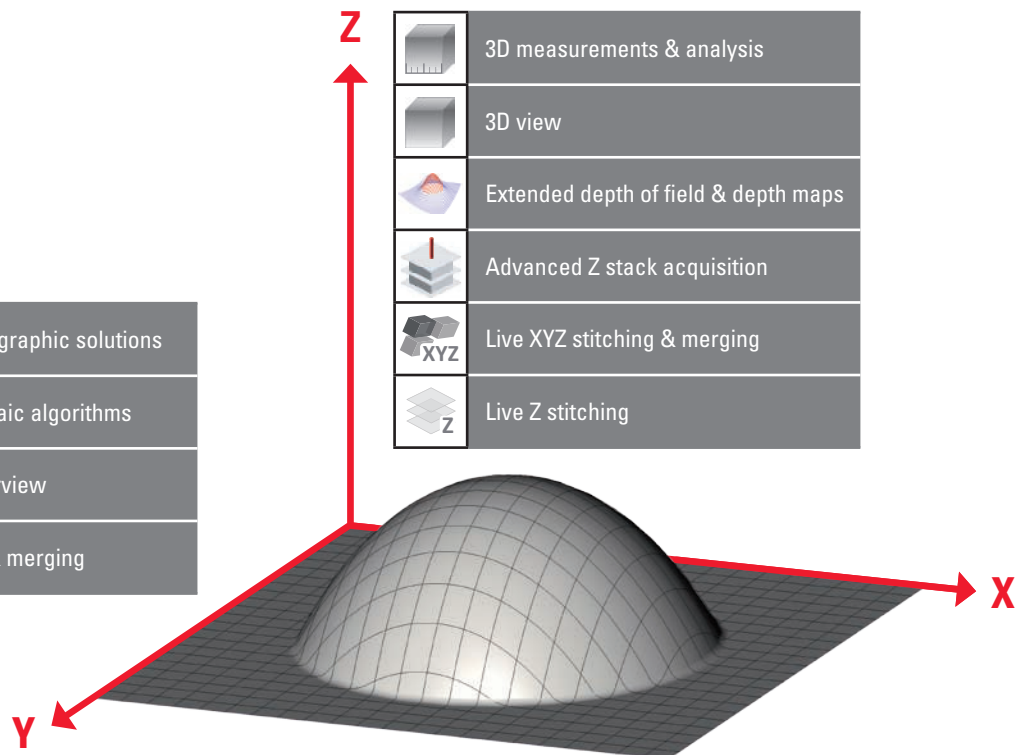
The software allows you to control your microscope and camera in x, y, and z with your mouse.

Superior in any dimension for multi-image analysis

- > If you work with large samples, you can create images that are bigger than the maximum field of view. Expand the visible area with live stitching and merging functions in x, y, and z to 2D and 3D images.
- > Analyze and measure your sample with 3D models and depth maps.
- > Create new perspectives on your sample by generating top views from any viewing angle.
- > Dedicated analysis modules with expanded functionalities are designed to help you with specific applications, e.g. metallography.

	Dedicated metallographic solutions
	Advanced 2D mosaic algorithms
	2D navigation overview
	Live XY stitching & merging

	3D measurements & analysis
	3D view
	Extended depth of field & depth maps
	Advanced Z stack acquisition
	Live XYZ stitching & merging
	Live Z stitching



SPECIFICATIONS

IMAGE ACQUISITION & PROCESSING	LAS X CORE	OPTIONAL SOFTWARE MODULES
Basic image acquisition	●	–
Imaging parameter recall	●	–
HDR acquisition	●	–
Basic image processing tools (crop, resize, sharpening, color adjustment, background filter, median, blur)	●	–
Visual comparison view	●	–
Software autofocus ^①	● ^②	● ^③
Digital comparison reticules	–	●
Movie recording (avi format, expandable by additional video codecs)	–	●
Time lapse	–	●
CUSTOMIZATION AND DOCUMENTATION		
Documentation reports ^④ (customizable, example templates included)	●	–
Measurement & analysis reports ^④ (customizable, example templates included)	●	–
Customizable user interface layout	●	–
Basic annotation	●	–
Extended annotation	–	●
Multi-user profiles	●	–
Multi-user access level management	–	●
MEASUREMENT & ANALYSIS		
Basic measurement	●	–
2D measurement over multiple field of view (including live image long distance measurements)	–	●
2D image analysis (customizable particle/area analysis and trainable classifiers)	–	●
2D multichannel analysis (parallel analysis of multiple datasets and logical operations between datasets)	–	●
Phase analysis (including multiphase particle counting and surface/interface analysis)	–	●
Dedicated metallographic analyses (manual stereological measurements, phase analysis, grain size analysis, optical decarburization depth analysis and nodular cast iron analysis)	–	●
2D XY EXPANSION		
2D navigation overview	●	–
Live image builder XY (for live stitching & merging)	–	●
2D mosaic tilescan and spiralscan	–	●
3D Z AND XYZ EXPANSION		
Z stack acquisition	●	–
Live Z stitching	–	●
Live XYZ stitching	–	●
Extended depth of field (EDOF) & depth map calculation	–	●
3D surface view & edit	–	●
3D surface measurement & analysis	–	●
Export to Leica Maps ^⑤	●	–

① requires Leica microscope with motorized Z-axis or external motorized Z-axis

② for Leica industrial compound microscopes

③ for all other Leica microscopes

④ requires Microsoft Office

⑤ requires Leica Map software (not included)

CONNECT
WITH US!



Leica Microsystems (Schweiz) AG · Max-Schmidheiny-Strasse 201 · 9435 Heerbrugg, Switzerland
T +41 71 726 34 34 · F +41 71 726 34 44

www.leica-microsystems.com